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<p>Substitute for form 1449A/PTO</p> <p>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</p> <p>(use as many sheets as necessary)</p>				<p><i>Complete if Known</i></p> <table border="1"> <tr> <td>Application Number</td> <td>09/362,192</td> </tr> <tr> <td>Filing Date</td> <td>July 28, 1999</td> </tr> <tr> <td>First Named Inventor</td> <td>Shunpei YAMAZAKI et al.</td> </tr> <tr> <td>Group Art Unit</td> <td>2812</td> </tr> <tr> <td>Examiner Name</td> <td>J. Simkovic</td> </tr> <tr> <td>Attorney Docket Number</td> <td>740756-2011</td> </tr> </table>		Application Number	09/362,192	Filing Date	July 28, 1999	First Named Inventor	Shunpei YAMAZAKI et al.	Group Art Unit	2812	Examiner Name	J. Simkovic	Attorney Docket Number	740756-2011
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Sheet	1	of	1														

U.S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

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8-83)U.S. Department of Commerce
Patent and Trademark Office

Atty Docket 0756-201

Serial No. 09/362,192

INFORMATION DISCLOSURE STATEMENT

FEB 11 2002

Applicants: Shunpei YAMAZAKI et al.

Filing Date: July 28, 1999

Group Art Unit: 2812

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
	5,147,826	09/15/1992	Liu et al.			
	5,262,350	11/16/1993	Yamazaki et al.			
	5,275,851	01/04/1994	Fonash et al.			
	5,278,093	01/11/1994	Yonehara			
	5,344,796	09/06/1994	Shin et al.			
	5,352,291	10/04/1994	Zhang et al.			
	5,387,542	02/07/1995	Yamamoto et al.			
	5,403,772	04/04/1995	Zhang et al.			
	5,424,230	06/13/1995	Wakai			
	5,486,237	01/23/1996	Sano et al.			
	5,488,000	01/30/1996	Zhang et al.			
	5,501,989	03/26/1996	Takayama et al.			
	5,529,937	06/25/1996	Zhang et al.			
	5,531,182	07/02/1996	Yonehara			
	5,550,070	08/27/1996	Funai et al.			
	5,578,520	11/26/1996	Zhang et al.			
	5,582,880	12/10/1996	Mochizuki et al.			
	5,654,203	08/05/1997	Ohtani et al.			
	5,766,360	06/16/1998	Sato et al.			
	5,840,118	11/24/1998	Yamazaki			
	5,843,225	12/01/1998	Takayama et al.			
	5,854,096	12/29/1998	Ohtani et al.			
	5,861,337	01/19/1999	Zhang et al.			
	5,873,942	02/23/1999	Park et al.			
	5,882,165	03/16/1999	Maydan et al.			
	5,900,105	05/04/1999	Toshima			
	5,923,968	07/13/1999	Yamazaki et al.			
	5,976,259	11/02/1999	Yamazaki			

Examiner

Date Considered

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TO-1449 REV. 8-83)	U.S. Department of Commerce Patent and Trademark Office	Atty Docket 0756-2011	Serial No. 09/362,192			
INFORMATION DISCLOSURE STATEMENT <i>O I P E</i> <i>FEB 11 2002</i> <i>PATENT TRADEMARK</i>		Applicants: Shunpei YAMAZAKI et al.				
		Filing Date: July 28, 1999	Group Art Unit: 2812			
FOREIGN PATENT DOCUMENTS						
Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation Yes No
<i>[initials]</i>	04-035021	02/05/1992	JP			Eng Abst
<i>[initials]</i>	04-286336	10/12/1992	JP			Eng Abst
<i>[initials]</i>	WO 93/10555	05/27/1993	PCT			X
OTHER DOCUMENT (Including Author, Title, Date, Pertinent Pages, Etc.)						
Examiner Initial	<p><i>[initials]</i> Bonnel et al., "Polycrystalline Silicon Thin-Film Transistors with Two-Step Annealing Process", pp. 551-553, December 1993, IEEE Electron Device Letters, Vol. 14, No. 12</p> <p><i>[initials]</i> Fuse et al., "Performance of Poly-Si Thin Film Transistors Fabricated by Excimer-Laser Annealing of SiH₄- and SiH₂H₆- Source Low Pressure Vapor Deposited a-Si Films With or Without Solid-Phase Crystallization", pp. 565-570, 1994, Solid State Phenomena Vols. 37-38</p> <p><i>[initials]</i> Specifications for Application Serial No. 09/259,211, "Method of Manufacturing a Semiconductor Device and Manufacturing System Thereof" Attorney Docket No.: 07977/018002</p>					
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